



# Polarization effects in radiation damaged scCVD Diamond detectors

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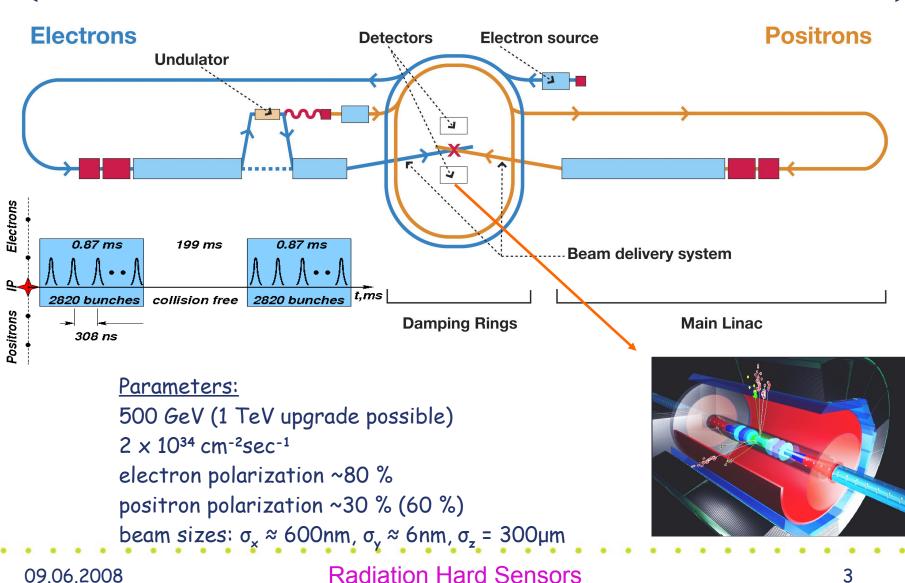
4<sup>th</sup> NoRHDia Workshop @ GSI

09.06.2008

- Why do we need Diamond Detector @ ILC?
- BeamCal challenge
- Diamond properties
- Charge collection
  - Ideal crystal, Radiation damaged crystal
- Polarization creation, model
- Experimental studies:
  - CCD vs Dose, CCD time dependence
  - Future plans
- Summary

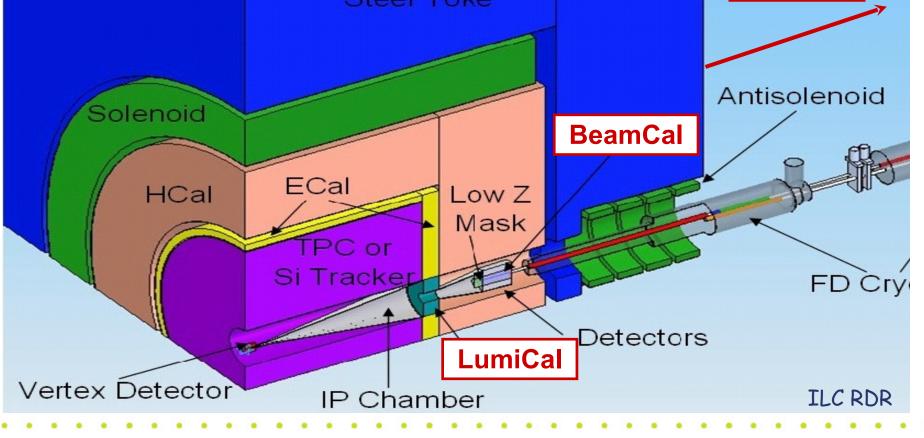
## The International Linear Collider İι

~30km



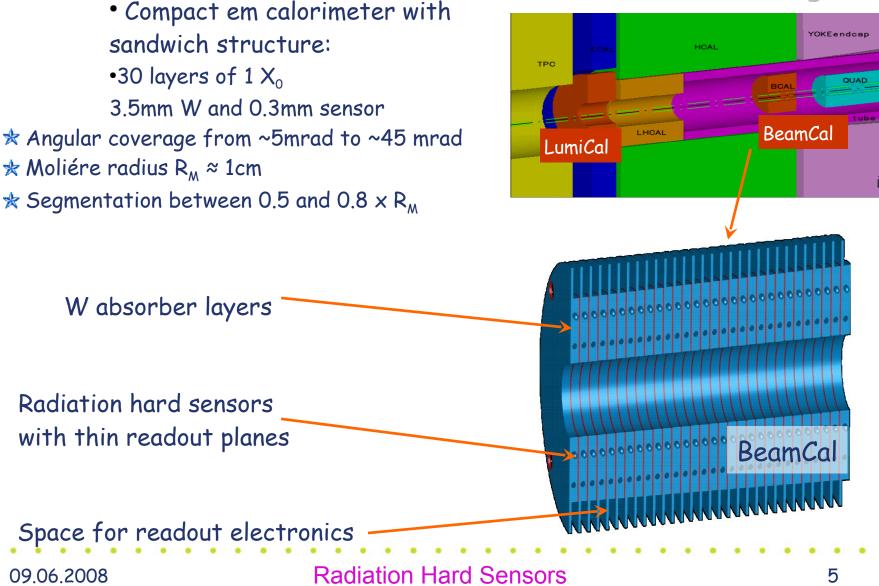
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# Design of the Forward Region



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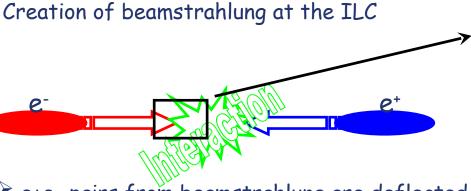
## BeamCal Design

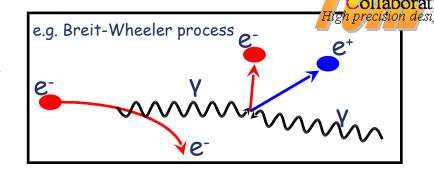


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Collaborat

# The Challenges for BeamCal





e+e- pairs from beamstrahlung are deflected into the BeamCal

≻15000 e⁺e⁻ per BX

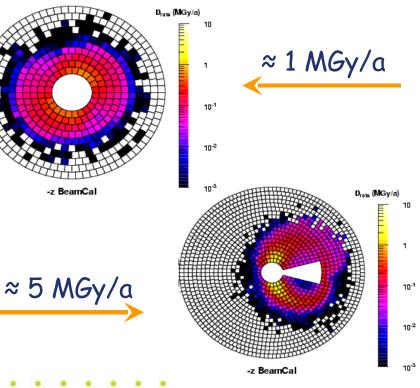
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=> 10 - 20 TeV total energy dep.

~ 10 MGy per year strongly dependent on the beam and magnetic field configuration

=> radiation hard sensors

Detect the signature of single high energetic particles on top of the background.



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# **Diamond properties**

- $\blacktriangleright$  Density 3.52 g cm<sup>-3</sup>
- Dielectric constant 5.7
- Breakdown field 10<sup>7</sup> V cm<sup>-1</sup>
- $\sim$  Resistivity  $>10^{11} \Omega$  cm
- ➢ Band Gap 5.5 eV
- Electron mobility 1800 (4500) cm<sup>2</sup> V<sup>-1</sup> s<sup>-1</sup>
- Hole mobility 1200 (3800) cm<sup>2</sup> V<sup>-1</sup> s<sup>-1</sup>
- Energy to create e-h pair 13.1 eV
- > Average signal created 36 e  $\mu m^{-1}$

\* High-purity single crystal CVD



Sensors

## sc CVD diamond from Element 6 (provided by GSI, Darmstadt)

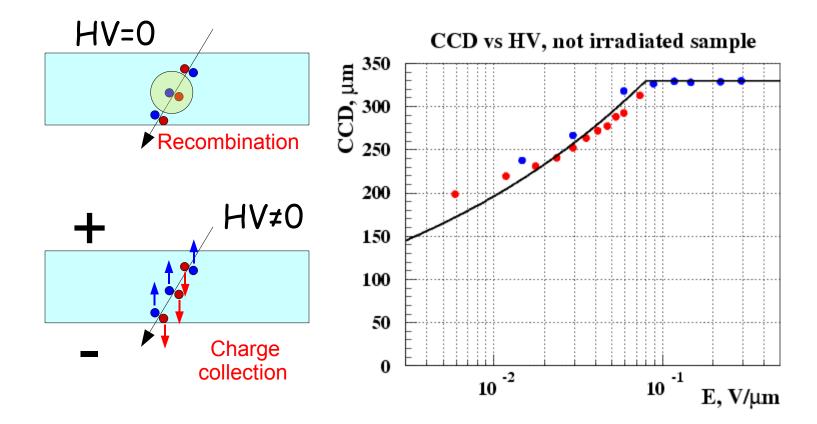
Thickness 326  $\mu$ m, active area 3mm in diameter



2 sensors, one is irradiated up to 5 MGy dose at the 10 MeV electron beam in 2007

# 'Ideal' crystal charge collection

## Charge collection efficiency depends on E

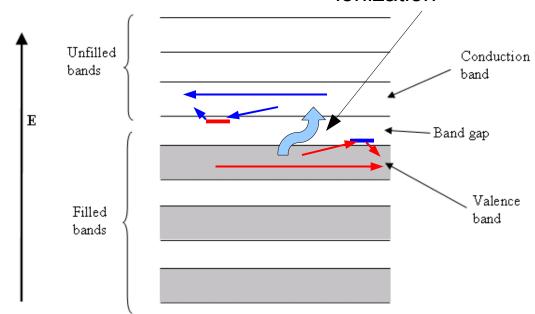


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**Radiation Hard Sensors** 

# Radiation damaged crystal

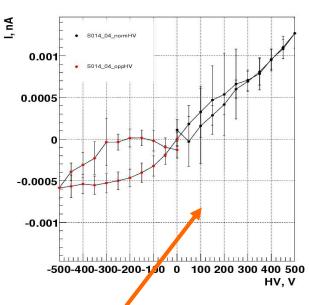
- Radiation causes local damages of the lattice structure.
- These local damages (traps) are able to capture free charge carriers and release them after some time
- Assumptions:
- Trap density is uniform (bulk radiation damage)
- Traps are created independently (linearity vs dose)



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## Irradiation of single crystal CVD Diamond

<u>After absorbing 5 MGy:</u> <u>CVD diamonds still operational.</u> CCD (from I<sub>sens</sub>) vs dose ccb [µm] 400 350 CCD (from source setup) 300 250 200 150 100 50 0<sub>0</sub> 1000 5000 2000 3000 4000 dose [kGy]



So14 04

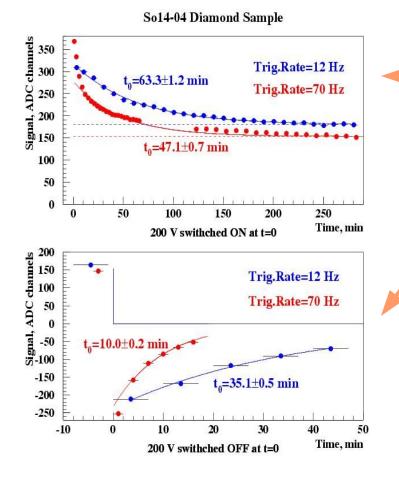
Very low leakage currents (~pA) after the irradiation.

Decrease of the charge collection distance with the dose.

Generation of trapping centers
 due to irradiation. Traps release?
 Strong polarization effects !!!

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## After absorbing 5 MGy:



Measurements at <sup>90</sup>Sr-source setup:

After switching HV on signal drops with time

Switching HV off after signal stabilization: strong signal of opposite polarity is observed

Signal time behavior depends on the MIPs rate

**Dynamic polarization!** 

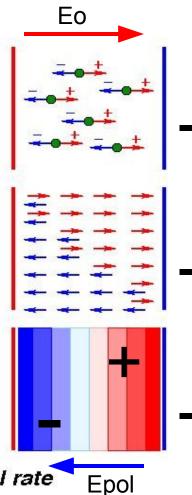
Model of sCVD Diamond Polarization

## **Polarization Model**

Radiation damage – uniformly produced traps MIP signal – uniformly produced e–h pairs +Electric field 
NONUNIFORM space charge Change of the electric field e–h Recombination if the field is low Release of trapped charges (decay time) Change of the space charge distribution +

## Steady state POLARIZATION

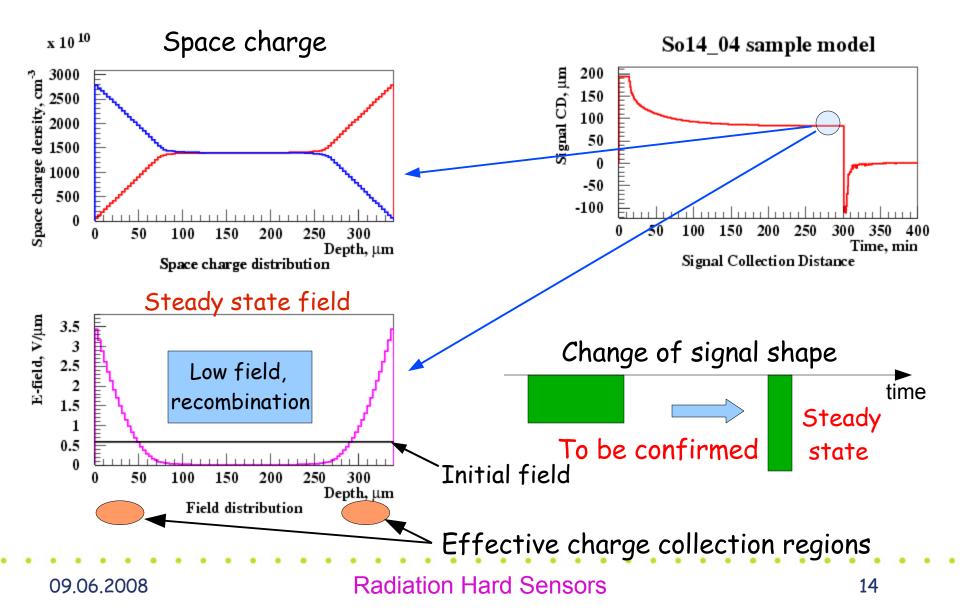
Dependent on trap density, applied voltage and signal rate



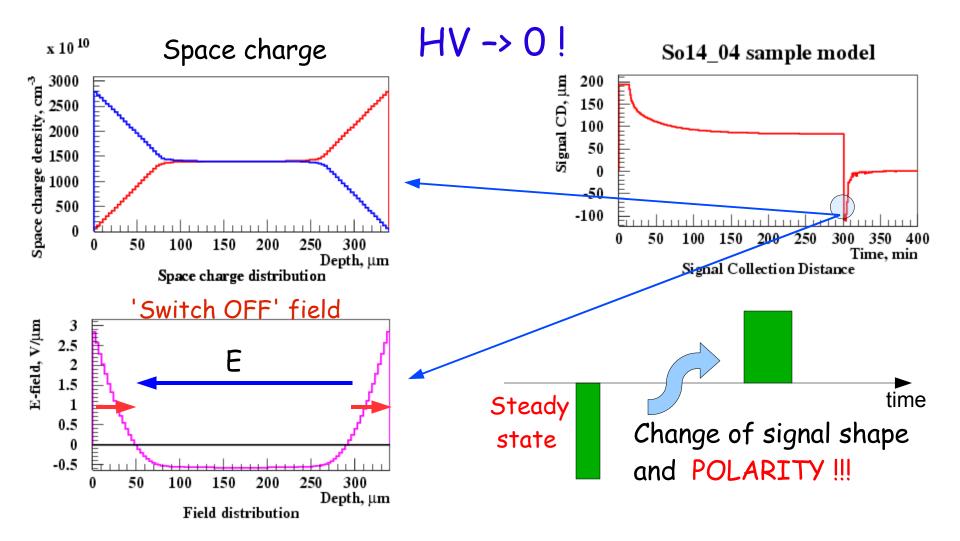
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# Model of sCVD Diamond Polarization - 1



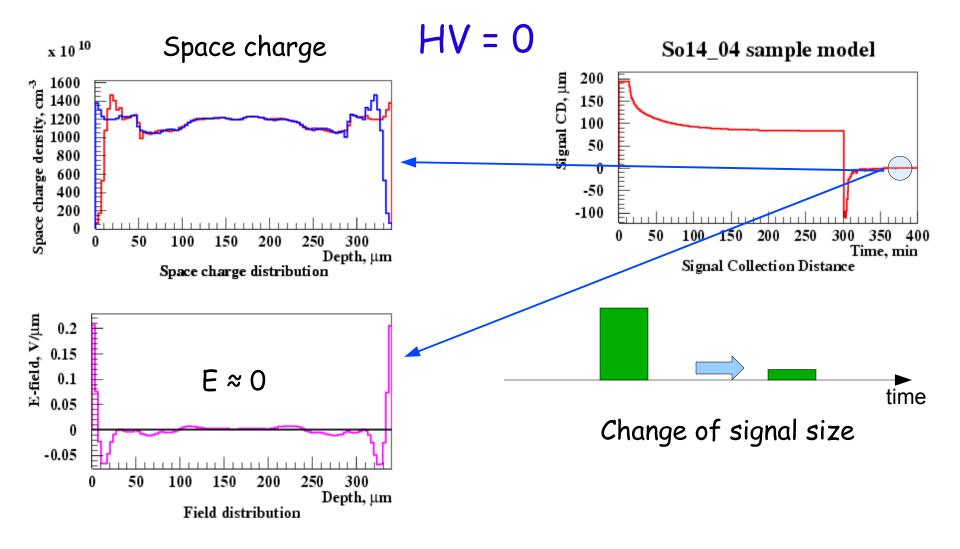
Model of sCVD Diamond Polarization - 2



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Model of sCVD Diamond Polarization - 3

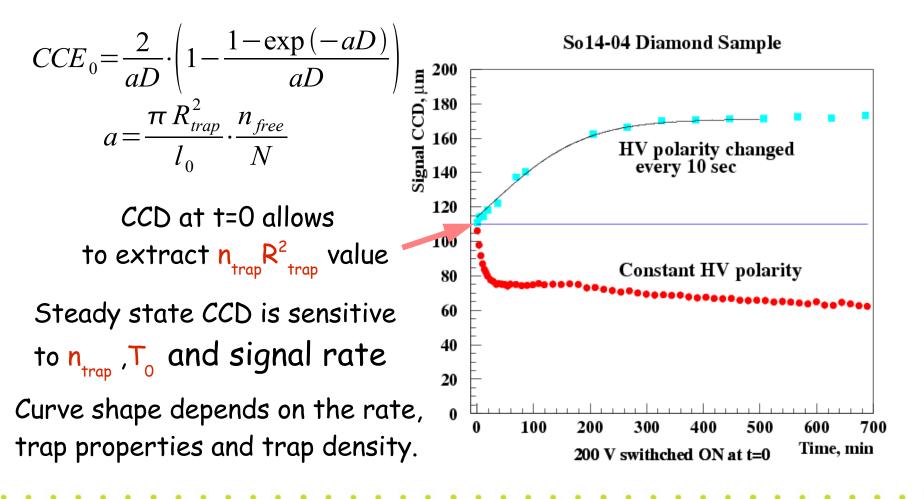


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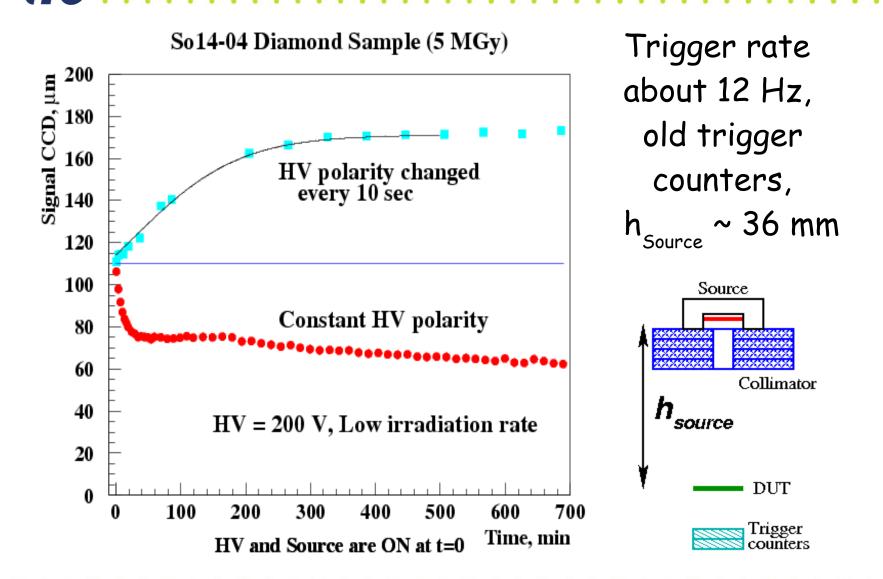
# <sup>90</sup>Sr setup: CCD time dependence

## Diamond sCVD sensor after 5 MGy



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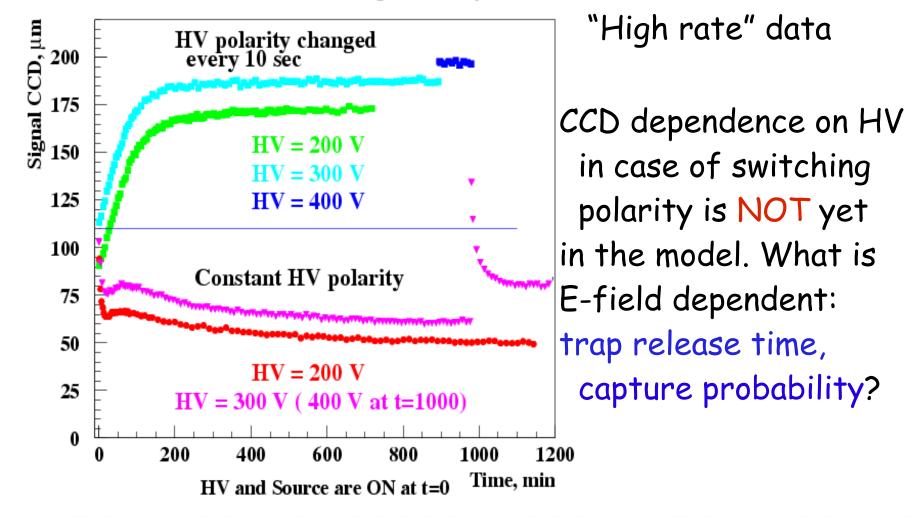
# CCD vs time dependence, low rate



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# CCD vs time, different HV

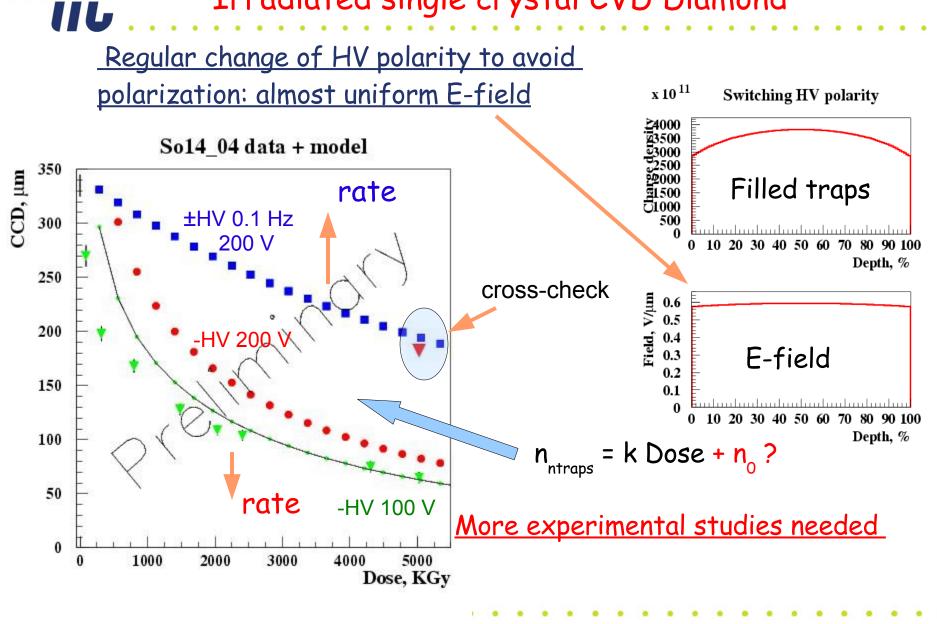
So14-04 Diamond Sample (5 MGy)



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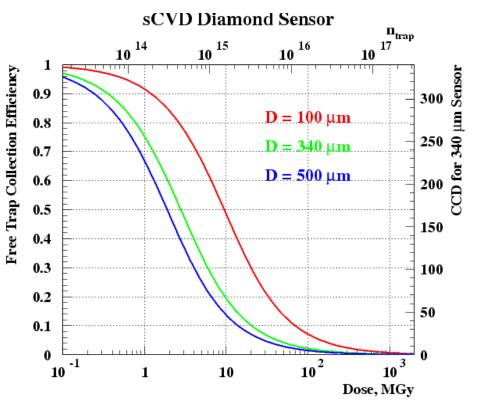
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## Irradiated single crystal CVD Diamond



Charge absorption probability for the thin layer:

$$P_{l} = 1 - \exp\left(-\pi R_{trap}^{2} \cdot \frac{l}{l_{0}} \cdot \frac{n_{free}}{N}\right) = 1 - e^{-al}$$



In case when free traps are uniformly distributed:

 $a = \frac{\pi R_{trap}^2}{l_0} \cdot \frac{n_{free}}{N}$ 

Charge collection efficiency could be calculated analytically. For the detector of thickness D:

$$CCE_0 = \frac{2}{aD} \cdot \left(1 - \frac{1 - \exp(-aD)}{aD}\right)$$

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## Summary

- Strong polarization effect is observed in the radiation damaged scCVD Diamond detector.
- It was shown that the polarization significantly decreases the detector charge collection efficiency.
- A simple model is developed in order to understand and describe observed phenomena.
- Method of routinely switching HV polarity is proposed to suppress polarization. Large improvement of CCE is observed experimentally.
- More work is needed to understand CCD dependence on the signal rate and details of polarization development.
- It is desirable to continue test beam studies up to higher doses (approx 50 MGy) and measure sensor CCD @ ILC-like conditions.



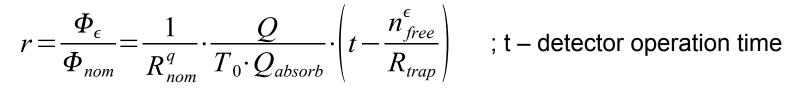
# Thank you...

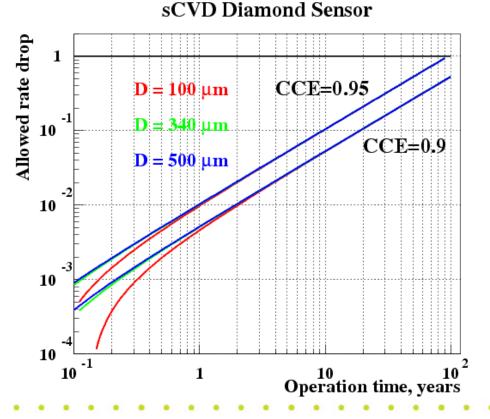
# Special thanks to GSI team: CVDD sensors, test beam etc.

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# Uniformly (partly) filled traps

Allowed reduction of the flux keeping  $\varepsilon$  efficiency:





Alternating HV polarity + + stable particle flux = = XXL radiation hardness

Charge collection efficiency could be kept at high level for a very long time if particle flux is maintained stable.

Leakage current ??? Crystal destruction ???

**Radiation Hard Sensors**